



**PATENT**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

**In re Application of:**

Farnworth et al.

**Serial No.:** 10/669,949

**Filed:** September 24, 2003

**For:** WAFER-LEVEL TESTING  
APPARATUS AND METHOD

**Confirmation No.:** 4767

**Examiner:** M. Trinh

**Group Art Unit:** 2822

**Attorney Docket No.:** 2269-5467.1US  
(02-0309.01/US)

**Notice of Allowance Mailed:**

September 23, 2004

**NOTICE OF EXPRESS MAILING**

Express Mail Mailing Label Number: EL994824581US

Date of Deposit with USPS: December 22, 2004

Person making Deposit: Steven P. Wong

**AMENDMENT PURSUANT TO 37 C.F.R. § 1.312(a)**

Mail Stop ISSUE FEE  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

Sir:

Please amend the above-referenced application as follows:

**Amendments to the Specification** begin on page 3 of this paper.

**Amendments to the Claims** are reflected in the listing of claims which begins on page 5 of this paper.

*OK to enter  
312 dated 12/22/04  
M.T.*